#### TOSHIBA BIPOLAR DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

# TD62476P,TD62477P,TD62478P,TD62479P

#### 2CH PERIPHERAL AND / NAND / OR / NOR DRIVERS

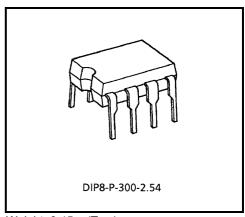
The TD62476P, TD62477P, TD62478P, TD62479P are comprised of two NPN single output stages and control inputs which can gate the outputs.

All units feature integral clamp diodes for switching inductive loads

Applications include relay, hammer, lamp and display (LED) drivers.

#### **FEATURES**

- Output current (single output) 350 mA (Max)
- High sustaining voltage output 35 V (Min)
- Output clamp diodes
- Inputs compatible with TTL and 5 V CMOS
- Standard supply voltage
- Package type-P: DIP-8 pin

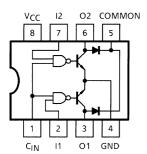


Weight: 0.45 g (Typ.)

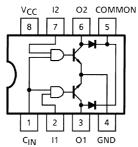
	TD6247	6P	TD62477P			TD62478P			TD62479P			
INPUT		OUTPUT	INPUT		OUTPUT	INPUT		OUTPUT	INPUT		OUTPUT	
$C_IN$	I	0011 01	C <sub>IN</sub>	1 001101		C <sub>IN</sub>		0011 01	C <sub>IN</sub>		0011 01	
0	0	ON	0	0	OFF	0	0	ON	0	0	OFF	
0	1	OFF	0	1	OFF	0	1	OFF	0	1	ON	
1	0	OFF	1	0	OFF	1	0	OFF	1	0	ON	
1	1	OFF	1	1	ON	1	1	OFF	1	1	ON	

## **PIN CONNECTION (TOP VIEW)**



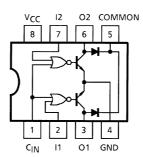


TD62477P

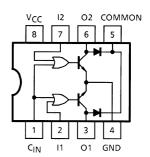


TD62478P

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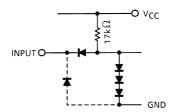
TD62479P



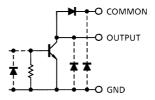


## **EQUIVALENT OF INPUTS AND OUTPUTS**

#### Equivalent of inputs



#### Equivalent of outputs



Note: The input and output parasitic diodes cannot be used as clamp diodes.

# **MAXIMUM RATINGS (Ta = 25°C)**

CHARACTERISTICS	SYMBOL	RATING	UNIT
Supply Voltage	V <sub>CC</sub>	-0.5~7.0	V
Input Voltage	V <sub>IN</sub>	-0.5~5.5	V
Output Sustaining Voltage	V <sub>CE</sub> (SUS)	-0.5~35	V
Output Current	lout	350	mA / ch
Clamp Diode Reverse Voltage	V <sub>R</sub>	35	V
Clamp Diode Forward Current	lF	300	mA
Power Dissipation	P <sub>D</sub> (Note)	0.9	W
Operating Temperature	T <sub>opr</sub>	-30~75	°C
Storage Temperature	T <sub>stg</sub>	-55~150	°C

Note: Delated above 25°C in the proportion of 7.2 mW / °C.

# RECOMMENDED OPERATING CONDITIONS ( $Ta = -30 \sim 75$ °C)

CHARACTERISTIC	SYMBOL	CONDITION	MIN	TYP.	MAX	UNIT
Supply Voltage	V <sub>CC</sub>	_	4.5	5.0	5.5	V
Output Sustaining Voltage	V <sub>CE</sub> (SUS)	_	0	_	35	V
Output Current	lour	DC 1 Circuit	0	_	300	mA /
Output Current	lout	DC 2 Circuits	0	_	200	ch
Input Voltage	V <sub>IN</sub>	_	4.5	_	V <sub>CC</sub>	V
Clamp Diode Reverse Voltage	V <sub>R</sub>	_	_	_	35	V
Clamp Diode Forward Current	I <sub>F</sub>	_	_	_	300	mA
Power Dissipation	PD	_	_	_	0.4	W

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# ELECTRICAL CHARACTERISTICS (Ta = 25°C)

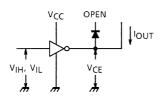
C	CHARACTERISTIC				TEST CIR- CUIT	TEST C	NOITIONC	MIN	TYP.	MAX	UNIT
Input Volto	Input Voltage		el el	V <sub>IH</sub>	1	_		2.0	_	_	V
input voita	ige	"L" Lev	el	V <sub>IL</sub>	1			_	_	0.8	v
Output Cu	Output Current		rel	I <sub>OH</sub>	2	V <sub>CC</sub> = 4.5V, V <sub>IH</sub> = 2.0 V V <sub>IL</sub> = 0.8V, V <sub>OH</sub> = 35 V		_	-	10	μΑ
	Output Voltage			V <sub>OL</sub>	3	V <sub>CC</sub> = 4.5 V V <sub>IH</sub> = 2.0 V	I <sub>OUT</sub> = 100 mA	_	0.15	0.30	V
Output Vo			el				I <sub>OUT</sub> = 200 mA	_	0.28	0.45	
						V <sub>IL</sub> = 0.8 V	I <sub>OUT</sub> = 300 mA	_	0.45	- 0.8 10 0.30	
		"H" Level		I <sub>IH</sub>	4	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 5.5 V		ı	_	10	μΑ
Input Curr	ent		I	lu 5		V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 0.4 V		١	-0.26	-0.4	mA
			C <sub>IN</sub>	I <sub>IL</sub>	J	VCC 5.5 V, VIN - 0.4 V		1	-0.52	-0.8	111/5
Clamp Dio	Clamp Diode Reverse Current			I <sub>R</sub>	6	$V_{CC}$ = 4.5 V, $V_R$ = 35 V		1	_	10	μΑ
Clamp Dio	Clamp Diode Forward Voltage			V <sub>F</sub>	7	V <sub>CC</sub> = 4.5 V, I <sub>F</sub>	_	1.5	1.75	V	
		TD624	76P		5	- V <sub>CC</sub> = 5.5 V	V <sub>IN</sub> = 5 V	_	8.4	14	mA
	Output	TD624	77P				V <sub>IN</sub> = 0 V	_	0.6	0.85	
	Off	TD624	78P	Іссн			V <sub>IN</sub> = 5 V	_	9	14	
Supply		TD624	79P				V <sub>IN</sub> = 0 V	-	1.1	1.8	
Current	Output On	TD624	76P				V <sub>IN</sub> = 5 V	-	38	55	
		TD62477P	I <sub>CCL</sub>	4		V <sub>IN</sub> = 0 V	_	36	53	- -	
		TD62478P				V <sub>IN</sub> = 5 V	_	39	56		
		TD6247	79P				V <sub>IN</sub> = 0 V	_	36	63	İ

# **SWITCHING CHARACTERISTICS (Ta = 25°C)**

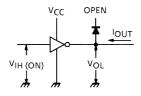
CHARACTERIS	SYMBOL	TEST CIR- CUIT	CONDITION	MIN	TYP.	MAX	UNIT	
Propagation Delay	"H" Level	t <sub>pLH</sub>	_	C <sub>1</sub> = 15 pF P <sub>1</sub> = 1200	1	0.7	-	μs
Time	"L" Level	t <sub>pHL</sub>	_	$C_L = 15 \text{ pF}, R_L = 120\Omega$	_	0.2	_	μδ

#### **TEST CIRCUIT**

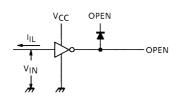
## 1. VIH, VIL



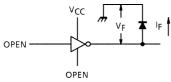
## 3. Vol



## 5. I<sub>IL</sub>, I<sub>CCH</sub>

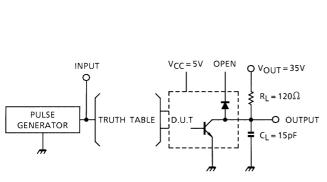


#### 7. V<sub>F</sub>

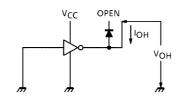


# TEST CIRCUIT OF SWITCHING CHARACTERISTIC

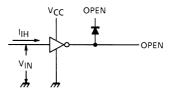
# OPEN



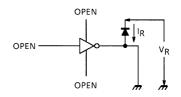
# 2. I<sub>OH</sub>



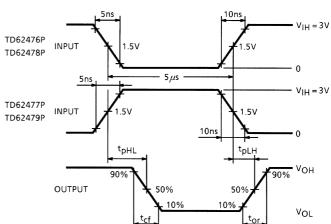
#### 4. I<sub>IH</sub>, I<sub>CCL</sub>



#### 6. I<sub>R</sub>



# TEST WAVEFORM



#### **PRECAUTIONS for USING**

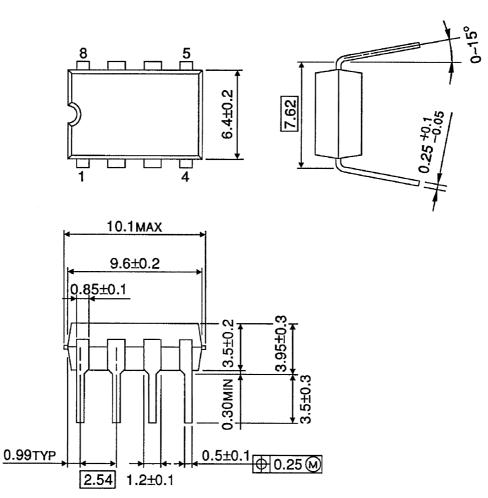
This IC does not integrate protection circuits such as overcurrent and overvoltage protectors.

Thus, if excess current or voltage is applied to the IC, the IC may be damaged. Please design the IC so that excess current or voltage will not be applied to the IC.

Utmost care is necessary in the design of the output line, VCC, COMMON and GND line since IC may be destroyed due to short–circuit between outputs, air contamination fault, or fault by improper grounding

## **PACKAGE DIMENSIONS**

DIP8-P-300-2.54 Unit: mm



Weight: 0.45 g (Typ.)

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# RESTRICTIONS ON PRODUCT USE

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